华润微电子(重庆)有限公司

CRJQF41N65GCF

SJMOS N-MOSFET 650V, 42mΩ, 77A

Features

- CRM(CQ) Super_Junction technology
- Much lower Ron*A performance for On-state efficiency
- Better efficiency due to very low FOM
- Ultra-fast body diode
- Qualified for industrial grade applications according to JEDEC

Applications

- LED/LCD/PDP TV and monitor Lighting
- Solar/Renewable/UPS-Micro Inverter System
- Charger
- Power Supply

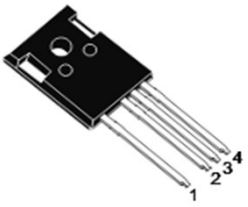
Product Summary

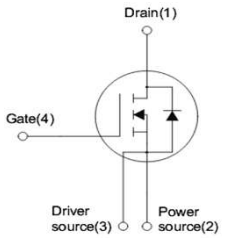
VDS	650V
$R_{DS(on)\_typ}$	42mΩ
I_D	77A

100% DVDS Tested

100% Avalanche Tested

RoHS HF





Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRJQF41N65GCF	CRJQF41N65GCF	TO-247-4L	Tube	N/A	N/A	25/30pcs

Absolute Maximum Ratings(at Tj = 25 °C, unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	650	V
Continuous drain current [1)] T_C = 25°C T_C = 100°C	I_D	77 48	A
Pulsed drain current [2)] (T_C = 25°C, t_p limited by T_{jmax})	$I_{D\ pulse}$	230	A
Avalanche energy, single pulse (L=30mH)	E_{AS}	1500	mJ
MOSFET dv/dt ruggedness	dv/dt	50	V/ns
Gate-Source voltage	V_{GS}	±30	V
Power dissipation (T_C = 25°C)	P_{tot}	687	W
Continuous diode forward current(T_C = 25°C)	I_S	77	A
Diode pulse current [2)] (T_C = 25°C)	$I_{S\ pulse}$	230	A
Recovery diode dv/dt [3)]	dv/dt	50	V/ns
Maximum diode commutation speed	di_F/dt	900	A/μs
Operating junction and storage temperature	T_j , T_{stg}	-55...+150	°C

1) Limited by Tj,max. Maximum Duty Cycle D = 0.50; TO-220 equivalent
2) Pulse width tp limited by Tj,max
3) Identical low side and high side switch with identical RG

Thermal Resistance

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Thermal resistance, junction – case	R_{thJC}	-	0.13	0.18	°C/W	
Thermal resistance, junction – ambient	R_{thJA}	-	-	45	°C/W	

Electrical Characteristic (at Tj = 25 °C, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Static Characteristic						
Drain-source breakdown voltage	BV_{DSS}	650	-	-	V	V_{GS}=0V, I_D=250uA
Gate threshold voltage	$V_{GS(th)}$	3.3	-	4.6	V	V_{DS}=V_{GS},I_D=250uA
Zero gate voltage drain current	I_{DSS}	- -	- 1000	5 -	μA	V_{DS}=650V,V_{GS}=0V T_j=25°C T_j=150°C
Gate-source leakage current	I_{GSS}	-	-	±100	nA	V_{GS}=±30V,V_{DS}=0V
Drain-source on-state resistance	$R_{DS(on)}$	- -	42 110	48 -	mΩ	V_{GS}=10V, I_D=35A, T_j=25°C T_j=150°C
Transconductance	g_{fs}	-	44	-	S	V_{DS}=20V,I_D=35A
Dynamic Characteristic						
Input Capacitance	C_{iss}	-	6594	-	pF	V_{GS}=0V, V_{DS}=100V, f=1MHz
Output Capacitance	C_{oss}	-	245	-		
Reverse Transfer Capacitance	C_{rss}	-	2.4	-		
Gate Total Charge	Q_G	-	168	-	nC	V_{GS}=10V, V_{DS}=480V, I_D=35A
Gate-Source charge	Q_{gs}	-	57	-		
Gate-Drain charge	Q_{gd}	-	88	-		
Gate plateau voltage	$V_{plateau}$	-	8.2	-	V	
Turn-on delay time	$t_{d(on)}$	-	179	-	ns	V_{GS}=10V, I_D=35A, V_{DS}=400V, R_g=27Ω
Rise time	t_r	-	115	-		
Turn-off delay time	$t_{d(off)}$	-	312	-		
Fall time	t_f	-	104	-		
Gate resistance	Rgint	0.2	1.0	2	Ω	V_{GS}=0V, V_{DS}=0V, f=1MHz

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V_{SD}	0.7	0.9	1.2	V	V_{GS}=0V,I_{SD}=35A
Body Diode Reverse Recovery Time	t_{rr}	-	194	-	ns	Isd=35A dI/dt=100A/us, Vds=400V
Body Diode Reverse Recovery Charge	Q_{rr}	-	1.5	-	uC	
Body Diode Reverse Recovery Peak Current	I_{rrm}	-	15	-	A	

Typical Performance Characteristics

Fig 1. Output Characteristics (Tj=25℃)

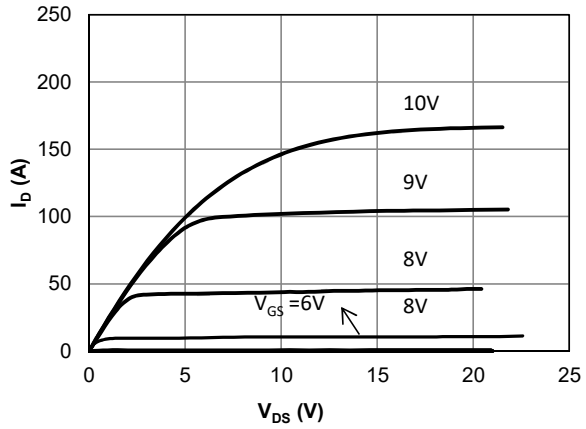


Fig 2. Output Characteristics (Tj=150℃)

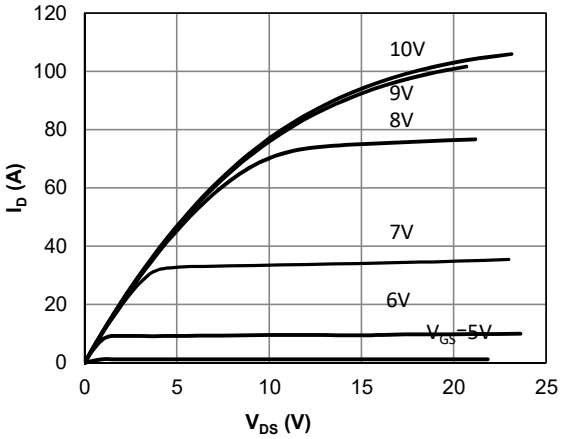


Fig 3: Transfer Characteristics

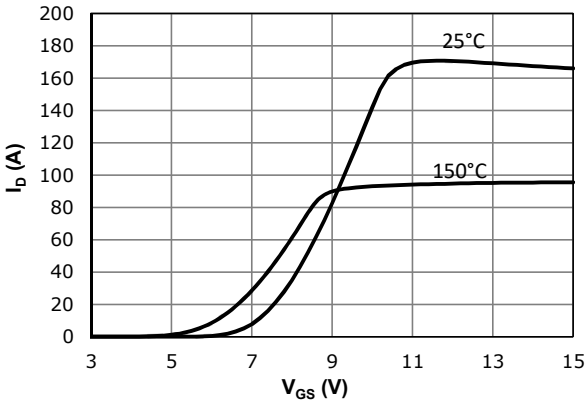


Fig 4: V_{TH} Vs Tj Temperature Characteristics

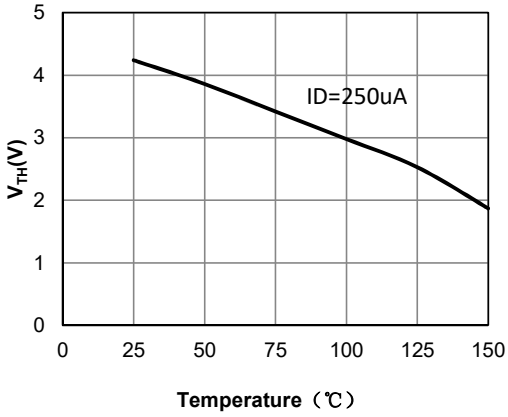


Fig 5: Rdson Vs Ids Characteristics(Tj=25℃)

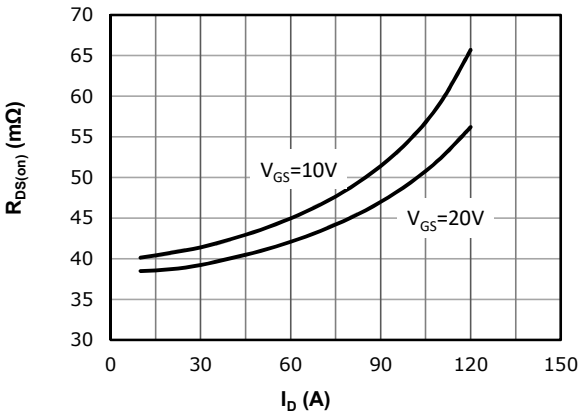


Fig 6: Rds(on) vs. Temperature

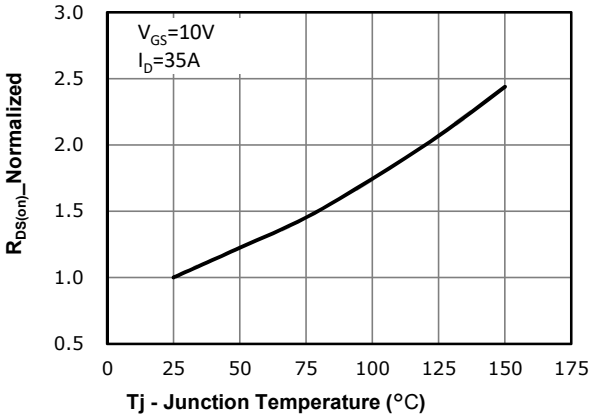


Fig 7: BVDSS vs. Temperature

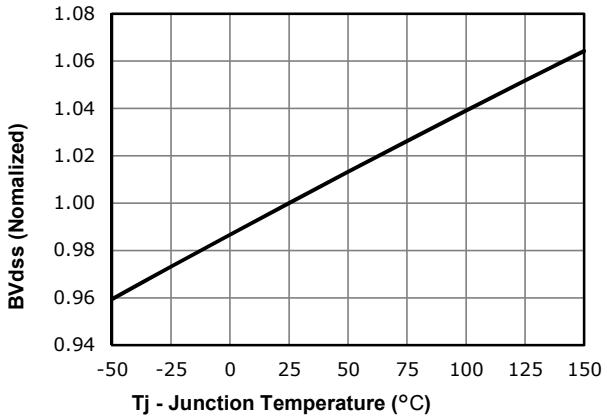


Fig 8: Rds(on) vs Gate Voltage

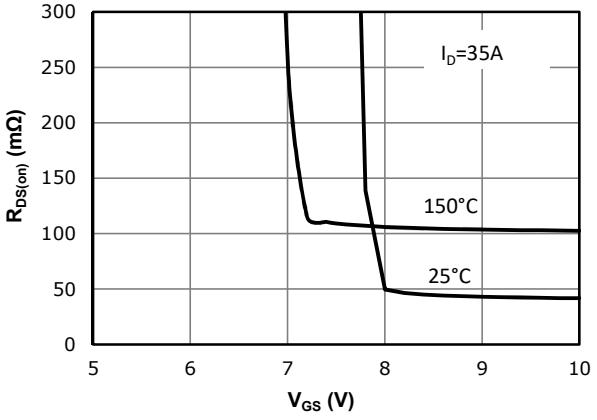


Fig 9: Body-diode Forward Characteristics

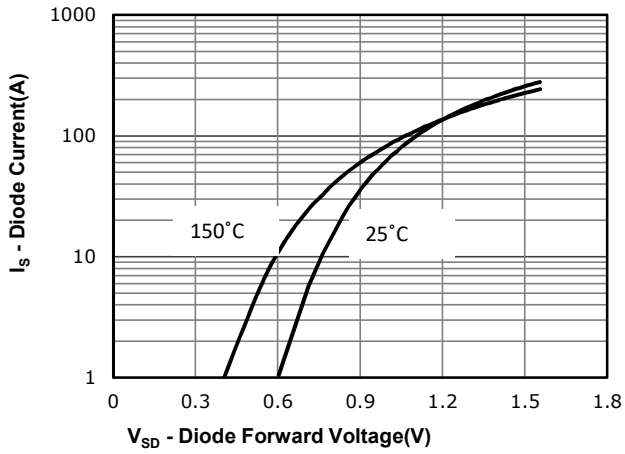


Fig 10: Gate Charge Characteristics

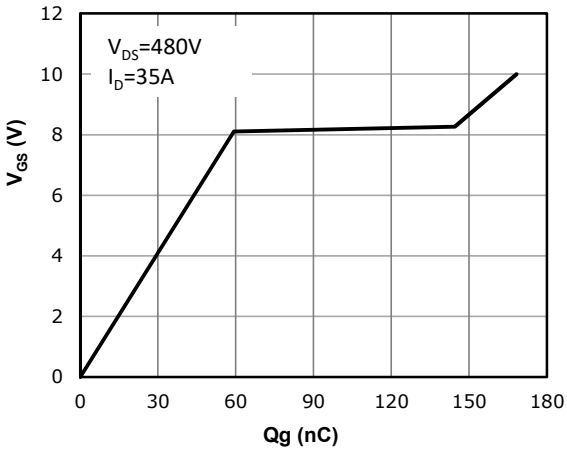


Fig 11: Capacitance Characteristics

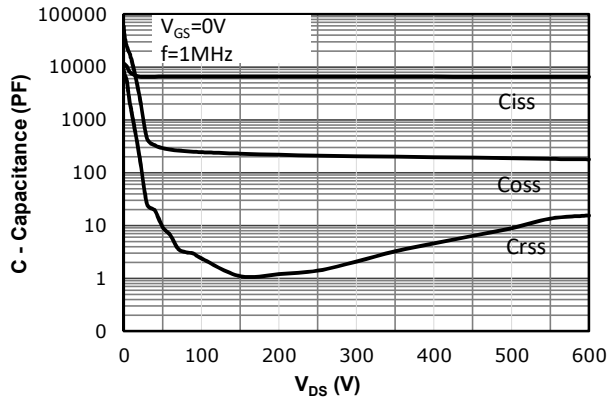


Fig 12: Safe Operating Area

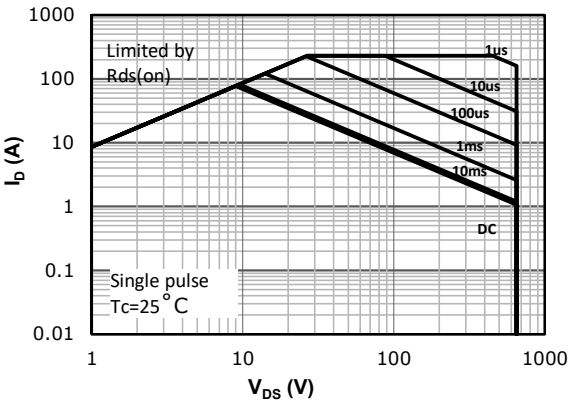
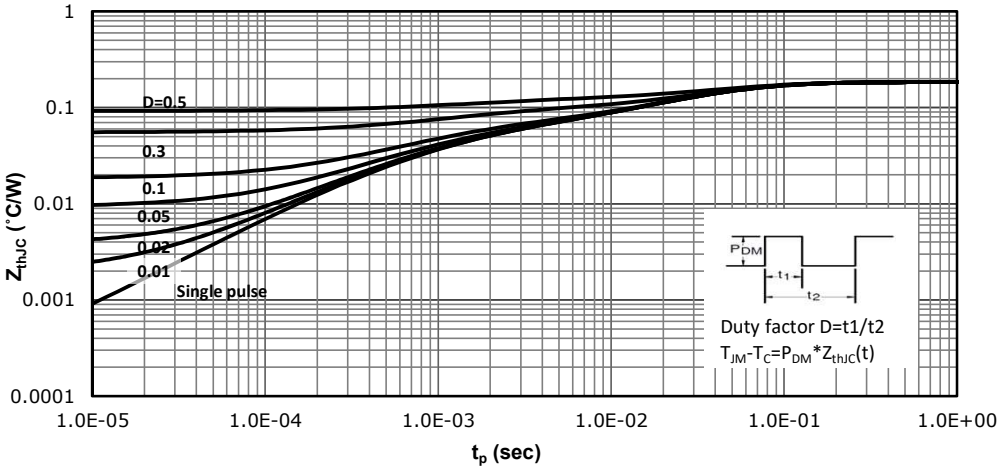
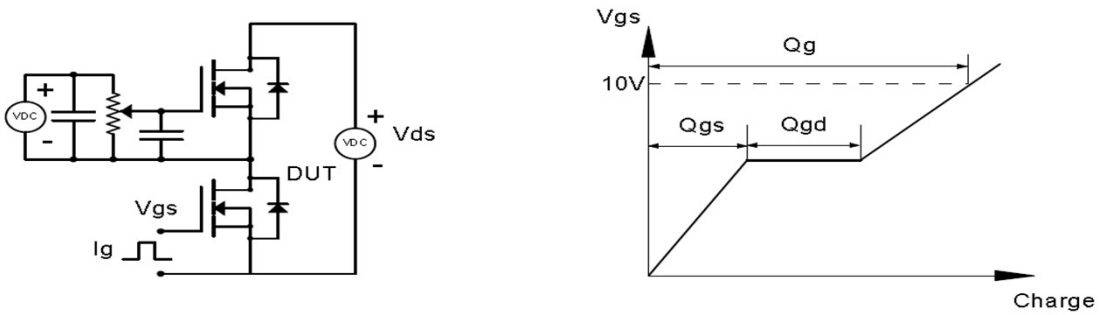


Fig 13: Max. Transient Thermal Impedance

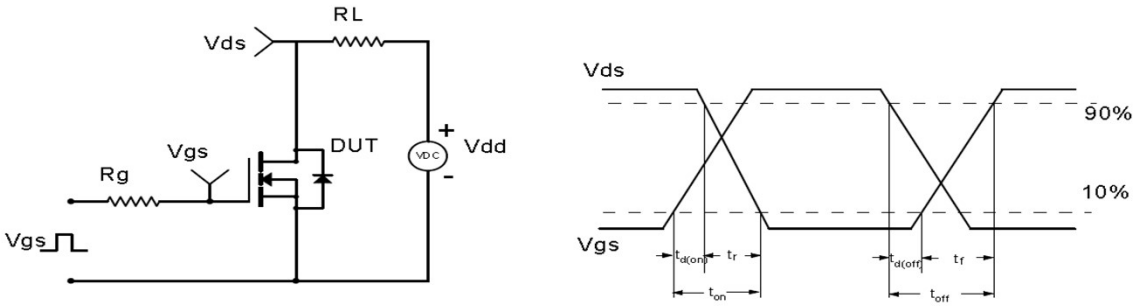


Test Circuit & Waveform

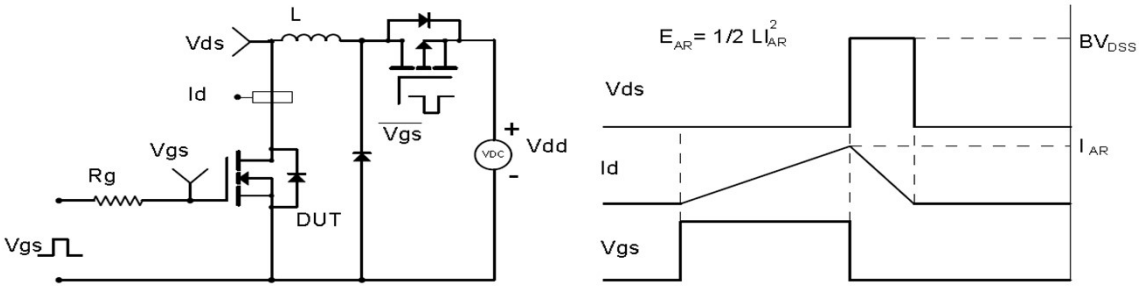
Gate Charge Test Circuit & Waveform



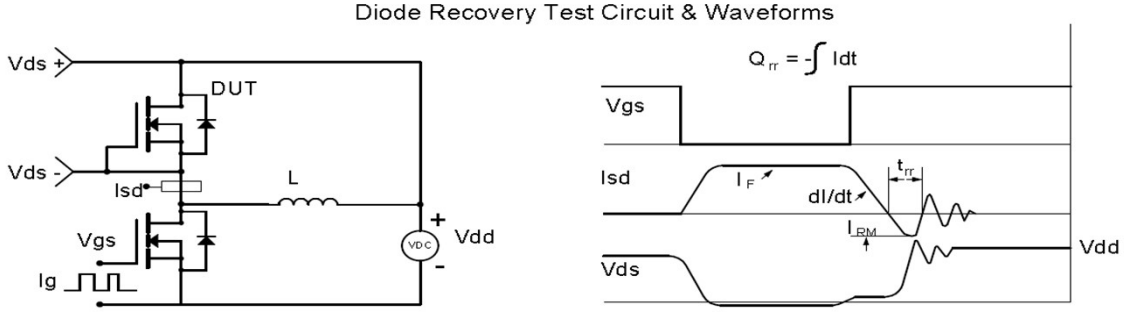
Resistive Switching Test Circuit & Waveforms



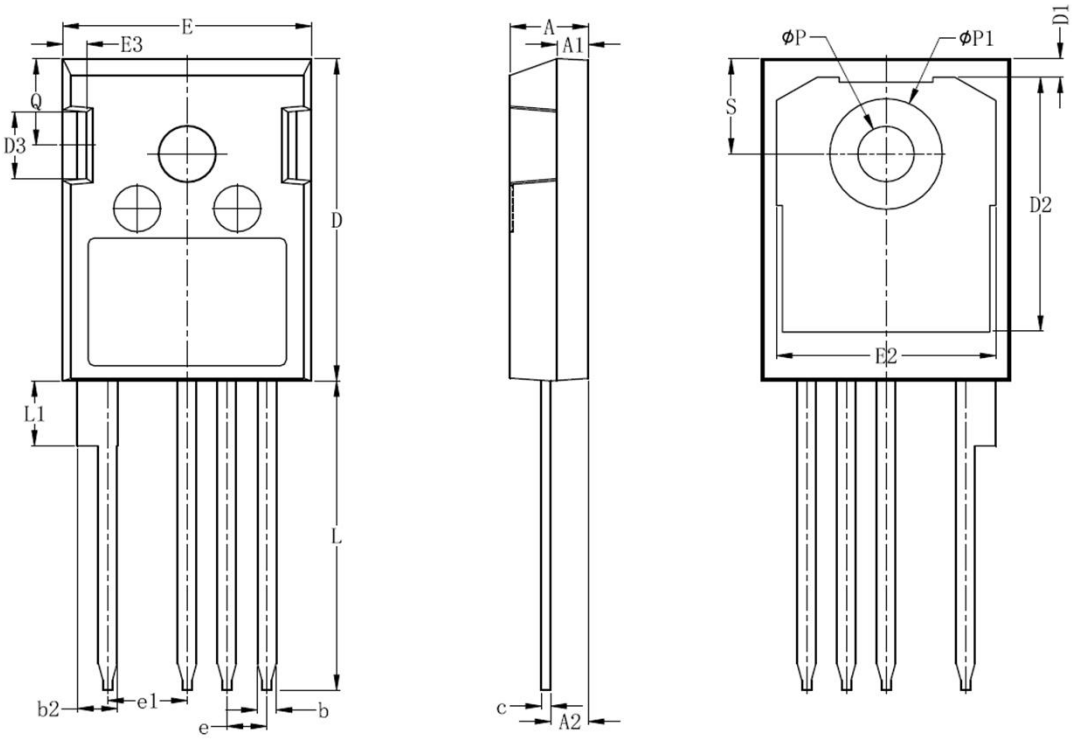
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Outline: TO-247-4L



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.83	5.21	0.190	0.205
A1	1.90	2.16	0.075	0.085
A2	2.20	2.60	0.087	0.102
b	1.07	1.34	0.042	0.053
b2	2.39	2.94	0.094	0.116
c	0.50	0.74	0.020	0.029
D	20.80	23.60	0.819	0.929
D1	0.95	1.43	0.037	0.056
D2	16.25	17.65	0.640	0.695
D3	3.68	5.10	0.145	0.201
e	2.54 BSC.		0.100 BSC.	
e1	5.08 BSC.		0.200 BSC.	
E	15.70	16.13	0.618	0.635
E2	13.10	14.23	0.516	0.560
E3	1.00	2.60	0.039	0.102
L	17.25	22.22	0.679	0.875
L1	3.94	4.43	0.155	0.174
P	3.50	3.70	0.138	0.146
P1	7.00	7.40	0.276	0.291
Q	5.33	6.00	0.210	0.236
S	6.00	6.40	0.236	0.252

Marking

NOTE:
NXBBAAAAY
X —Assembly location code
BB —Fab code
AAAA —Lot code
Y —Bin code

Revision History

Revison	Date	Major changes
2.1	2022/8/19	Update Package Outline

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qulified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semicondutor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

CRM(CQ) reserves the right to improve product design, function and reliability without notice.

单击下面可查看定价，库存，交付和生命周期等信息

>>CRMICRO(华润微)